

Search Notes**Application/Control No.**

10/718,192

Examiner

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Applicant(s)/Patent under Reexamination

KUO ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E23.101, E23.087 & E23.119	9/25/2006	C.C.
257	706 & 704	9/25/2006	C.C.
257	790 & 738	9/25/2006	C.C.
257	723 & 632	9/25/2006	C.C.
257	717 - 720	9/25/2006	C.C.
438	118 & 122	9/25/2006	C.C.
174	52.4	9/25/2006	C.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/25/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
As same	as above	9/25/2006	C.C.